

Notice of References Cited	Application/Control No. 10/788,420		Applicant(s)/Patent Under Reexamination BRANDWEIN, RICHARD PAUL	
	Examiner Siu M. Lee		Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0106038 A1	08-2002	Lee et al.	375/340
*	B	US-2002/0006097 A1	01-2002	Kim et al.	369/59.18
*	C	US-5,671,256	09-1997	Clark et al.	375/342
*	D	US-2003/0198163 A1	10-2003	Kim et al.	369/53.31
*	E	US-6,680,984	01-2004	Teghararian et al.	375/317
*	F	US-2005/0036568 A1	02-2005	De Ruijter et al.	375/316
*	G	US-2005/0141648 A1	06-2005	Lourens et al.	375/340
*	H	US-2001/0021144 A1	09-2001	Oshima et al.	369/13
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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